

METHOD AND SYSTEM OF TESTING COMPLEX MCM'S

ABSTRACT OF THE DISCLOSURE

5 A system and method for utilizing a multi-probe tester to test an electrical device having a plurality of contact pads. Multi-probe tester test probes and electrical device contact pads are arrayed in a common distribution pitch, and a means for masking test probes masks at least one test probe, thereby preventing the at least one test probe from returning a test result to the testing apparatus. In one embodiment the means for masking
10 test probes is a mask membrane physically preventing at least one test probe from making contact with the electrical device. In another embodiment, the means for masking is at least one software command configured to cause an input from at least one test probe to be disregarded during a test routine. Another embodiment features both mask membrane and software command probe masking.

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